

**Search Notes**

Application/Control No.

10/686,117

Examiner

Jinhee J. Lee

Applicant(s)/Patent under  
Reexamination

SUGAYA ET AL.

Art Unit

2831

**SEARCHED**

Class	Subclass	Date	Examiner
174	72A	2/18/2005	LEE
	100		
	117F		
439	404		
	395		
	443		
	405		
	67		
	422		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
174	as above	2/17/2005	LEE
439	as above	2/17/2005	Lee

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
N. Abrams	2/17/2005	LEE
East text search attached	2/18/2005	LEE